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TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (U-MOSIV)

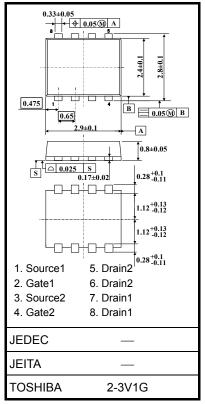
TPCP8302

Lithium Ion Battery Applications Notebook PC Applications Portable Equipment Applications

- Small footprint due to small and thin package
- Low drain-source ON-resistance: R_{DS(ON)} = 25 mΩ (typ.)
- High forward transfer admittance: |Y_{fs}| = 14 S (typ.)
- Low leakage current: $I_{DSS} = -10 \ \mu A \ (max) \ (V_{DS} = -20 \ V)$
- Enhancement mode: V_{th} = -0.4 to -1.0 V (V_{DS} = -6 V, I_D = -1 mA)

Absolute Maximum Ratings (Ta = 25°C)

Cha	racteristic	Symbol	Rating	Unit	
Drain-source voltage	ge	V _{DSS}	-20	V	
Drain-gate voltage	$(R_{GS} = 20 \text{ k}\Omega)$	V _{DGR}	-20	V	
Gate-source voltag	je	V _{GSS}	±12	V	
Drain current	DC (Note 1)	I _D	-20	А	
Drain current	Pulse (Note 1)	I _{DP}		A	
Drain power dissipation	Single-device operation (Note 3a)	P _{D (1)}	1.48	w	
(t = 5 s) (Note 2a)	Single-device value at dual operation (Note 3b)	P _{D (2)}	1.23		
Drain power dissipation	Single-device operation (Note 3a)	P _{D (1)}	0.58		
(t = 5 s) (Note 2b)	Single-device value at dual operation (Note 3b)	P _{D (2)}	0.58 0.36		
Single-pulse avala	nche energy (Note 4)	E _{AS}	6.5	mJ	
Avalanche current		I _{AR}	-5	А	
Repetitive avalanc Single-device value		E _{AR}	0.12	mJ	
Channel temperatu	ire	T _{ch}	150	°C	
Storage temperatu	re range	T _{stg}	–55 to 150 °C		



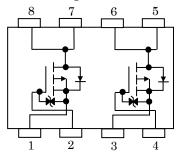
Weight: 0.017 g (typ.)

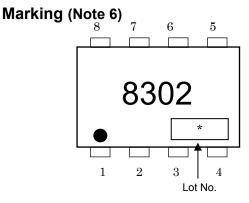
Note: For Notes 1 to 6, see the next page.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

This transistor is an electrostatic-sensitive device. Handle with care.

Circuit Configuration





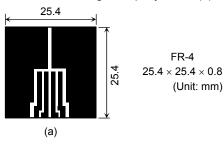
Unit: mm

Thermal Characteristics

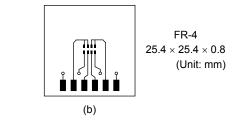
Characteristic		Symbol	Max	Unit	
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R _{th (ch-a) (1)}	84.5	°C/W	
(t = 5 s) (Note 2a)	Single-device value at dual operation (Note 3b)	R _{th (ch-a) (2)}	101.6		
Thermal resistance, channel to ambient	Single-device operation (Note 3a)			.5 °C/W	
(t = 5 s) (Note 2b)			347.2	C/VV	

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: (a) Device mounted on a glass-epoxy board (a)



(b) Device mounted on a glass-epoxy board (b)

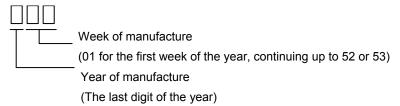


- Note 3: a) The power dissipation and thermal resistance values shown are for a single device. (During single-device operation, power is applied to one device only.)
 - b) The power dissipation and thermal resistance values shown are for a single device. (During dual operation, power is applied to both devices evenly.).

(Unit: mm)

- Note 4: $V_{DD} = -16 \text{ V}$, $T_{ch} = 25^{\circ}C$ (initial), L = 0.2 mH, $R_G = 25 \Omega$, $I_{AR} = -5 \text{ A}$
- Note 5: Repetitive rating: pulse width limited by maximum channel temperature
- Note 6: on the lower left of the marking indicates Pin 1.

* Weekly code (three digits):



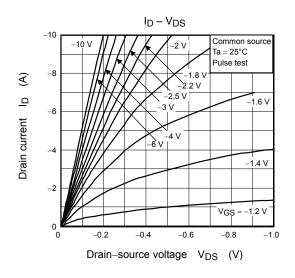
Electrical Characteristics (Ta = 25°C)

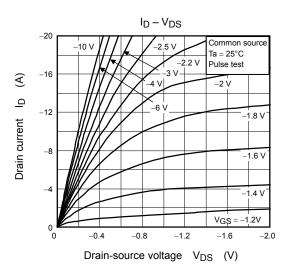
Ch	aracteristic	Symbol	Test Condition	Min	Тур.	Max	Unit	
Gate leakage cur	rrent	I _{GSS}	$V_{GS}=\pm 10~V,~V_{DS}=0~V$	_		±10	μA	
Drain cutoff curre	ent	I _{DSS}	$V_{DS} = -20 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	_		-10	μA	
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = -10$ mA, $V_{GS} = 0$ V	-20	_	_	V	
Diam-source bie	ardown voltage	V (BR) DSX	$I_D = -10$ mA, $V_{GS} = 12$ V	-8 — —		v		
Gate threshold ve	oltage	V _{th}	$V_{DS} = -6 V, I_D = -1 mA$	-0.4		-1.0	V	
		R _{DS (ON)}	$V_{GS} = -1.8 \text{ V}, I_D = -0.3 \text{ A}$	50 95		95		
Drain-source ON	-resistance	R _{DS (ON)}	$V_{GS} = -2.5 \text{ V}, \text{ I}_{D} = -2.5 \text{ A}$	_	33	45	mΩ	
		R _{DS (ON)}	$V_{GS} = -4 V, I_D = -2.5A$	_	25	33		
Forward transfer admittance		Y _{fs}	$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -2.5 \text{ A}$	7	14		S	
Input capacitance		C _{iss}	V _{DS} = -10 V, V _{GS} = 0 V, f = 1 MHz	_	1500	_	pF	
Reverse transfer capacitance		C _{rss}		_	220			
Output capacitance		C _{oss}		_	240			
Input capacitance Reverse transfer of Output capacitance Switching time	Rise time	tr	$V_{GS} \xrightarrow{0V} I_{D} = -2.5A$ $I_{D} = -2.5A$ OUT $G \xrightarrow{V} I_{T}$ $G \xrightarrow{V} I_{T}$ $V_{DD} \approx -10 V$	_	10	_		
	Turn-on time	t _{on}		_	20	_		
	Fall time	t _f			65	_	ns	
	Turn-off time	t _{off}	ν _{DD} ≈−10 v Duty ≤ 1%, t _w = 10 μs	_	200	-		
Total gate charge (gate-source plus gate-drain)		Qg	V _{DD} ≈ −16 V, V _{GS} = −5 V,		20	_		
Gate-source charge1		Q _{gs1}	$I_{\rm D} = -5 \rm{A}$		3.6		nC	
Gate-drain ("Miller") charge		Q _{gd}		_	5.1			

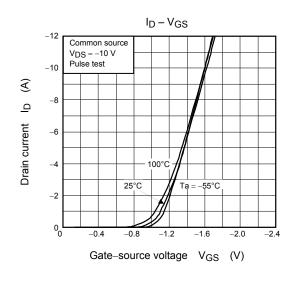
Source-Drain Ratings and Characteristics (Ta = 25°C)

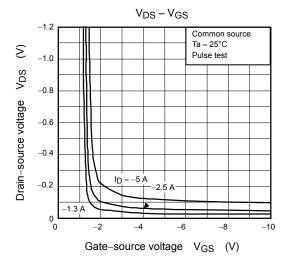
Characteris	tic	Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I _{DRP}	—	_	_	-20	А
Forward voltage (diode)		V _{DSF}	$I_{DR} = -5 \text{ A}, \text{ V}_{GS} = 0 \text{ V}$		_	1.2	V

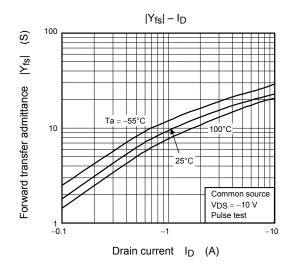
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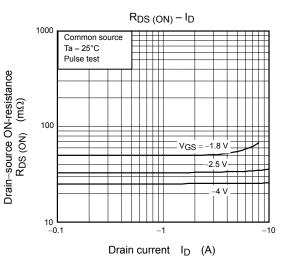




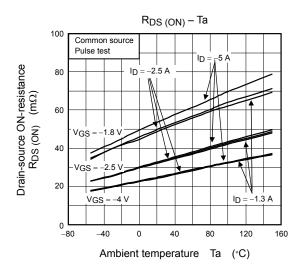


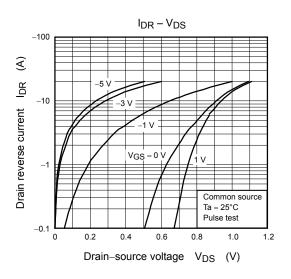


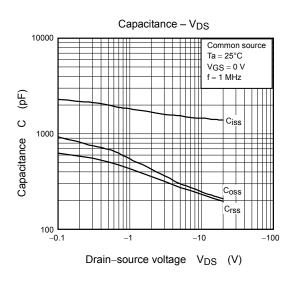


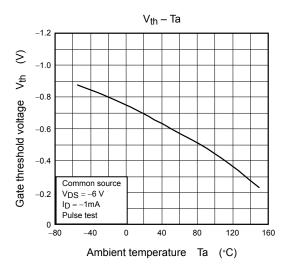


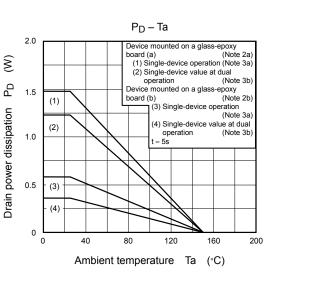
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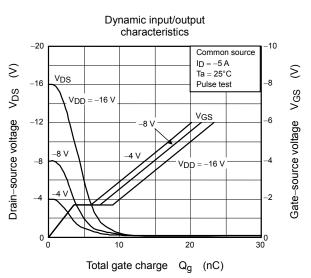


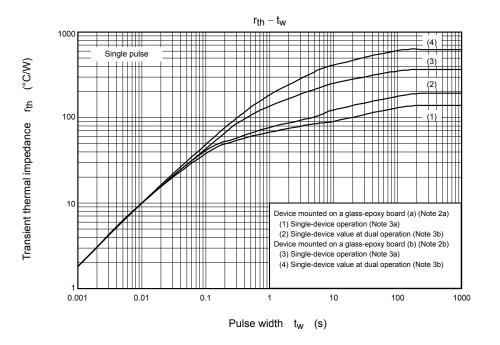




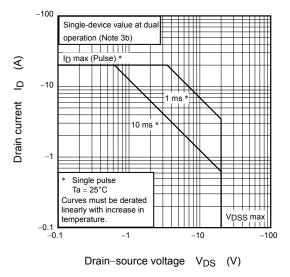








Safe operating area



RESTRICTIONS ON PRODUCT USE

20070701-EN GENERAL

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